

TEST REPORT

REPORT NUMBER: B15X50034-FCC-EMC_Rev1

ON

Type of Equipment: Ilium X100 Smart Phone

Type of Designation: Ilium X100

Manufacturer: Shenzhen fortuneship technology.LTD

ACCORDING TO Subpart B, PART 15, RADIO FREQUENCY DEVICES, Mar 6, 2015

China Telecommunication Technology Labs.

Month date, year April, 14, 2015

Signature

He Guili Director



Equipment: Ilium X100 REPORT NO.: B15X50034-FCC-EMC_Rev1

FCC ID: ZC4X100

Report Date: 2015-04-14

Test Firm Name: China Telecommunication Technology Labs

Registration Number: 840587

Statement

The measurements shown in this report were made in accordance with the procedures described on test pages. All reported tests were carried out on a sample equipment to demonstrate limited compliance with FCC CFR 47 Part 15. The sample tested was found to comply with the requirements defined in the applied rules.



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1 General Information

1.1 Notes

All reported tests were carried out on a sample equipment to demonstrate limited compliance with FCC CFR 47 Part15.

The test results of this test report relate exclusively to the item(s) tested as specified in section 2.

The following deviation from, additions to, or exclusions from the test specifications have been made. See Annex C.

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1.2 Testers

Name: Li Guoqing

Position: Engineer

Department: Department of EMC test

Date: 2015-04-14

Signature: 孝国庆

Editor of this test report:

Signature:

Signature:

Name: Li Guoqing

Position: Engineer

Department: Department of EMC test

Date: 2015-04-14

Technical responsibility for area of testing:

Name: Zou Dongyi

Position: Manager

Department: Department of EMC test

Date: 2015-04-14

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1.3 Testing Laboratory information

1 2 1	Location
1.3.1	LUCATION

Name: China Telecommunication Technology Labs.

Address: No. 11, Yue Tan Nan Jie, Xi Cheng District

BEIJING

P. R. CHINA, 100083

Tel: +86 10 68094078

Fax: +86 10 68011404

Email: emc@chinattl.com

1.3.2 Details of accreditation status

Accredited by: China National Accreditation Service for Conformity

Assessment (CNAS)

Registration number: CNAS Registration No. CNAS L0570

Standard: ISO/IEC 17025:2005

1.3.3 Test location, where different from section 1.3.1

Name: -----

Address: -----



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1.4 Details of applicant or manufacturer

1.4.1 Applicant

Name: CoroporativoLanix S.A. de C.V

Address: Carrtererainternacional Hermosillo-Nogales Km 8.5

Country: Mexico

Telephone: 6621090811

Fax: --

Contact: Oscar Guzman

Telephone: 6621090811

Email: Oguzman@lanix.ciim

1.4.2 Manufacturer (if different from applicant in section 1.4.1)

Name: Shenzhen fortuneship technology.,LTD

Address: 6th Floor, Kingson Building, New Energ Innovation

Industrial Park, No.1 Chuangsheng Road, Nanshan

District, Shenzhen P.R. China

City: Shenzhen

Country: China

1.4.3 Manufactory (if different from applicant in section 1.4.1)

Name: Shenzhen fortuneship technology, LTD

Address: 6th Floor, Kingson Building, New Energ Innovation

Industrial Park, No. 1 Chuangsheng Road, Nanshan

District, Shenzhen P.R. China

City: Shenzhen

Country: China



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2 Test Item

2.1 General Information

Manufacturer: Shenzhen fortuneshiptechnology.LTD

Name: Ilium X100 Smart Phone

Model Number: Ilium X100

Serial Number: --

Production Status: Product
Receipt date of test item: 2015-01-14

2.2 Outline of EUT

The EUT, Ilium X100 is a model supporting EDGE/GPRS/GSM 850/1900 bands, UMTS/HSDPA/HSUPA FDDII/V bands.

2.3 Modifications Incorporated in EUT

The EUT has not been modified from what is described by the brand name and unique type identification stated above.

2.4 Equipment Configuration

Equipment configuration list:

Item	Generic Description	Manufacturer	Туре	Serial No.	Remarks
A	Mobile Phone	Shenzhen fortuneship technology.LTD	Ilium X100 Smart Phone	ł	None
В	Battery	None	None		None
С	Adaptor	None	None		None

2.5 Other Information

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3 Summary of Test Results

A brief summary of the tests carried out is shown as following.

Configuration1		
Specification Clause	Name of Test	Result
15.109(a)	Radiated Emission	Pass
15.107(a)	Conducted Emission	Pass

Test eq	uipment Used:					
Number	Description	Manufacturer	Model Number	Serial Number	Cal Due	State
1	EMI Test Receiver	R/S	ESU	100367	2016-03-06	Normal
2	Ultra Broadband Antenna	R/S	VULB 9163	vulb9163-544	2015-12-13	Normal
3	Double-Ridged Horn Antenna	R/S	HF907	100357	2015-12-13	Normal
4	Fully-Anechoic Chamber	ETS	11.8m×6.5m×6.3m	- 1	2015-11-15	Normal
5	AMN	R/S	ENV216	101128	2016-03-06	Normal



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4 Test Results

4.1 Radiated Emission

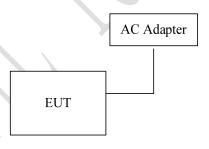
Specifications:	15.109(a)				
Date of Tests	2015-01-17-2015-01-28				
Test conditions:	Ambient Temperature:15℃-35℃	Ambient Temperature:15°C-35°C			
	Relative Humidity: 30%-60%				
	Air pressure: 86-106kPa				
Operation Mode	Normal	×			
Test Results:	Pass	10			

Limit Level Construction:

Frequency Range (MHz)	Quasi-Peak (dBuV/m)
30-88	40
88-216	43.5
216-960	46
Above 960	54

Frequency Range (MHz)	Peak (dBuV/m)	Average (dBuV/m)	
Above 1000	74	54	

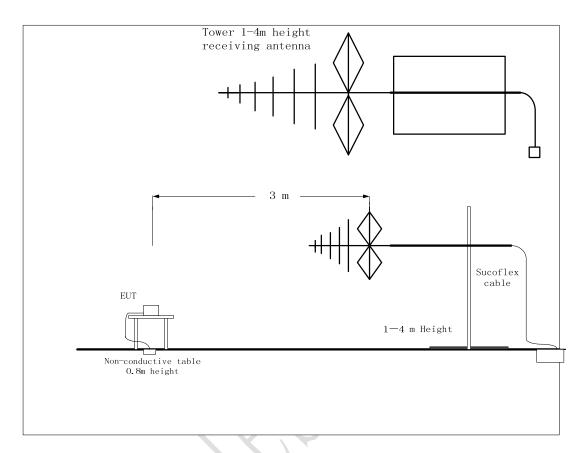
EUT Setup:





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Test Setup:



Test Method:

For 30-1000MHz, the EUT was placed on the top of a rotating 0.8-m table above the ground at a semi-anechoic chamber. The distance between the EUT and the received antenna was 3 meters. The table was rotated 360 degree and the received antenna mounted on a variable-height antenna tower was varied from 1m to 4m to find the maximum value of the field strength. Both horizontal and vertical polarizations of the antenna were set during the measurement. Tested in accordance with the procedures of ANSI C63.4-2014, section 8.3.

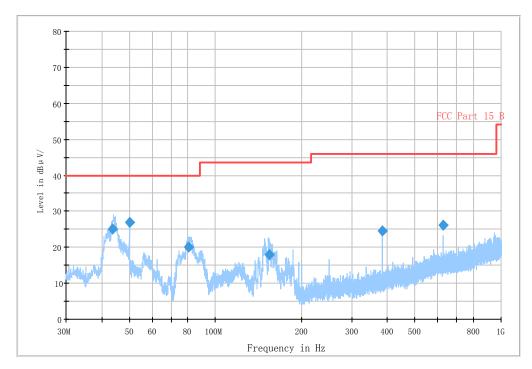
For 1000-12750MHz, the maximal emission value was acquired by adjusting the antenna height, and the table was rotated 360 degree to determine the maximum value of the field strength. Both horizontal and vertical polarizations of the antenna were set during the measurement.



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Test Data

RE - TX - GSM1900 + QP+PK 30M to 1G

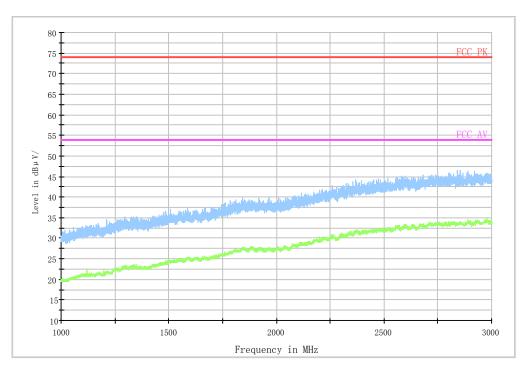


Frequency	QP	Mea.Time	RBW	Height	Polarity	Azimuth	Margin	Limit
MHz	dBuV/m	ms	KHz	cm	7	deg	dB	dBuV/m
43.745000	25.1	1000.0	120.0	99.0	V	265.0	14.9	40.0
50.022000	26.8	1000.0	120.0	126.0	V	5.0	13.2	40.0
80.596500	20.0	1000.0	120.0	228.0	Н	175.0	20.0	40.0
153.892000	18.0	1000.0	120.0	175.0	Н	175.0	25.5	43.5
384.001500	24.5	1000.0	120.0	99.0	Н	270.0	21.5	46.0
625.046500	26.2	1000.0	120.0	99.0	V	180.0	19.8	46.0

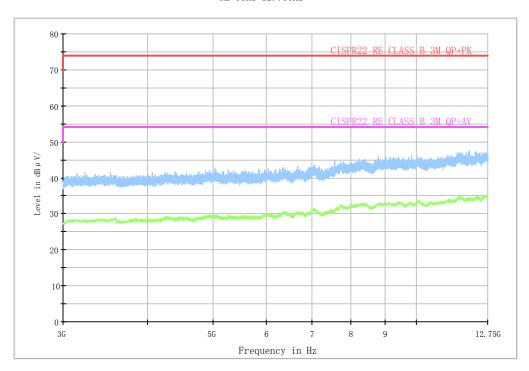


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RE 1GHz-3GHz



RE 3GHz-12.75GHz



Test photo

See the Pic1~3 in document" Ilium X100_EMC Test Setup Photos_Rev1".



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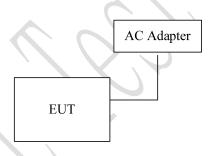
4.2 Conducted Emission

Specifications:	15.107(a)			
Date of Tests	2015-01-17-2015-01-25			
Test conditions:	Ambient Temperature:15°C-35°C			
	Relative Humidity:30%-60%			
	Air pressure: 86-106kPa			
Operation Mode	Normal			
Test Results:	Pass			

Limit Level Construction:

Frequency Range (MHz)	Conducted Limit (dBuV)			
	Quasi-peak	Average		
0.15-0.5	66 to 56*	56 to 46*		
0.5-5	56	46		
5-30	60	50		
*Decreases with the logarithm of the frequency				

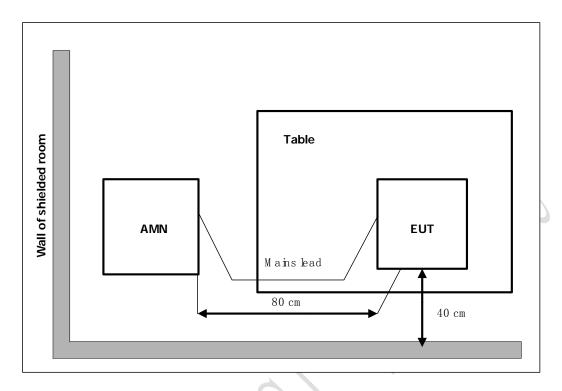
EUT Setup:





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Test Setup:



Test Method:

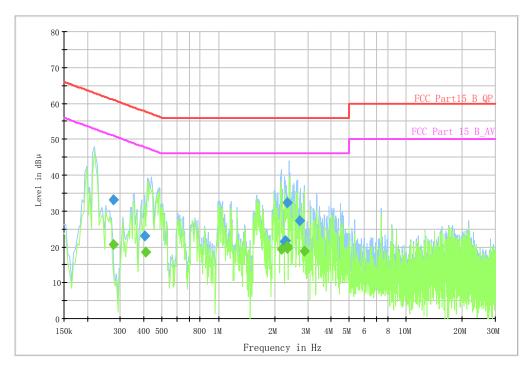
For equipment that is designed to be connected to the public utility (AC) power line, the radio frequency voltage that is conducted back onto the AC power line on any frequency or frequencies with the band 150 kHz to 30MHz shall not exceed the limits. Both lines of the power mains connected to the EUT were checked for maximum conducted interference. Tested in accordance with the procedures of ANSI C63.4-2014, section 7.3



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Test Data

CISPR N&L1 Voltage 150k to 30MHz-Class B $\,$



Frequency	QP	Mea.Time	Line	Margin	Limit
MHz	dBuV	ms		dB	dBuV
0.274000	33.2	1000.0	L1	27.8	61.0
0.403306	23.1	1000.0	L1	34.6	57.8
2.245144	21.6	1000.0	L1	34.4	56.0
2.264156	21.8	1000.0	L1	34.2	56.0
2.319288	32.4	1000.0	L1	23.6	56.0
2.725012	27.2	1000.0	L1	28.8	56.0

Frequency	AV	Mea.Time	Line	Margin	Limit
MHz	dBuV	ms		dB	dBuV
0.274000	20.6	1000.0	L1	30.4	51.0
0.410112	18.5	1000.0	L1	29.2	47.6
2.183144	19.3	1000.0	L1	26.7	46.0
2.318156	19.7	1000.0	L1	26.3	46.0
2.319019	20.1	1000.0	L1	26.0	46.0
2.864350	18.8	1000.0	L1	27.2	46.0

Test photo

See the Pic4 in document" Ilium X100_EMC Test Setup Photos_Rev1".



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Annex A External Photos

See the document" Ilium X100-External Photos".

Annex B Internal Photos

See the document"Ilium X100-Internal Photos".

ANNEX C Deviations from Prescribed Test Methods

No deviation from Prescribed Test Methods.

